

**General Description**

- Trench Power MV MOSFET technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- Optimized for fast-switching applications

**Applications**

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial

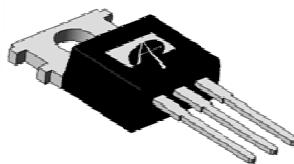
**Product Summary**

$V_{DS}$	40V
$I_D$ (at $V_{GS}=10V$ )	120A / 112A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 1.9mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 2.5mΩ

100% UIS Tested  
100%  $R_g$  Tested

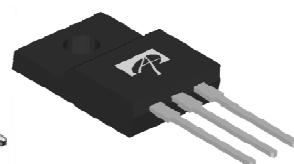
**Top View**

TO-220

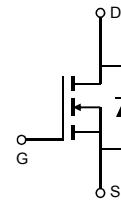


AOT2142L

TO-220F



AOTF2142L



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT2142L	TO-220	Tube	1000
AOTF2142L	TO-220F	Tube	1000

**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	AOT2142L(Max)	AOTF2142L(Max)	Units
Drain-Source Voltage	$V_{DS}$	40		V
Gate-Source Voltage	$V_{GS}$		$\pm 20$	V
Continuous Drain Current	$I_D$	120 <sup>G</sup>	112	A
$T_C=100^\circ C$	$I_D$	120 <sup>G</sup>	78	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	600		
Continuous Drain Current	$I_{DSM}$	50		A
$T_A=70^\circ C$	$I_{DSM}$	40		
Avalanche Current <sup>C</sup>	$I_{AS}$	60		A
Avalanche energy L=0.3mH <sup>C</sup>	$E_{AS}$	540		mJ
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	48	V
Power Dissipation <sup>B</sup>	$P_D$	312	41	W
$T_C=100^\circ C$	$P_D$	156	20	
Power Dissipation <sup>A</sup>	$P_{DSM}$	8.3		W
$T_A=70^\circ C$	$P_{DSM}$	5.3		
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175		°C

**Thermal Characteristics**

Parameter	Symbol	AOT2142L(Max)	AOTF2142L(Max)	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	15	15	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		60	60	°C/W
Maximum Junction-to-Case Steady-State	$R_{\theta JC}$	0.48	3.6	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	40			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.3	1.8	2.3	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		1.55	1.9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		2.25	2.8	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		100		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.66	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup> (AOT2142L)				120	A
$I_S$	Maximum Body-Diode Continuous Current (AOTF2142L)				50	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}, f=1\text{MHz}$		8320		pF
$C_{oss}$	Output Capacitance			1438		pF
$C_{rss}$	Reverse Transfer Capacitance			85		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	0.5	1.15	1.8	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, I_D=20\text{A}$		100		nC
$Q_g(4.5\text{V})$	Total Gate Charge			45		nC
$Q_{gs}$	Gate Source Charge			25		nC
$Q_{gd}$	Gate Drain Charge			7		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, R_L=1.0\Omega, R_{\text{GEN}}=3\Omega$		19		ns
$t_r$	Turn-On Rise Time			7		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			69		ns
$t_f$	Turn-Off Fall Time			10		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=400\text{A}/\mu\text{s}$		26		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=400\text{A}/\mu\text{s}$		83		nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{ C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{QJA}}$   $t \approx 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{ C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $175^\circ\text{ C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{ C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{ C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{QJC}}$  and case to ambient.

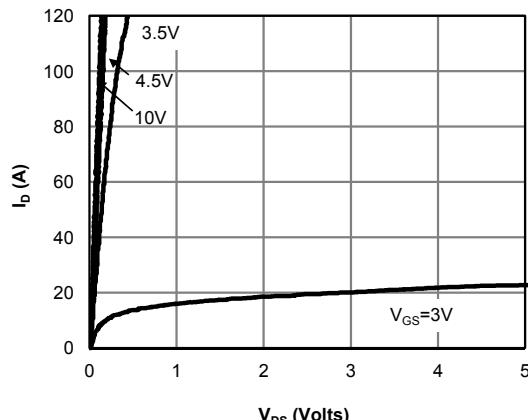
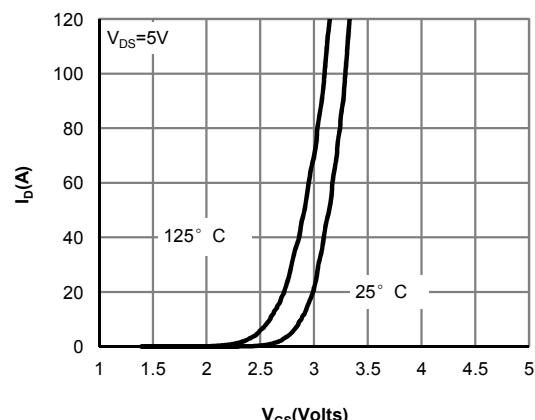
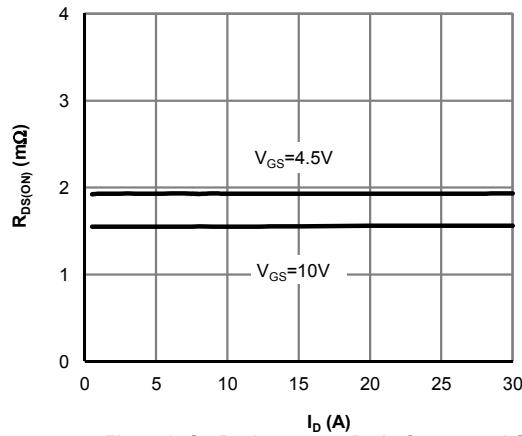
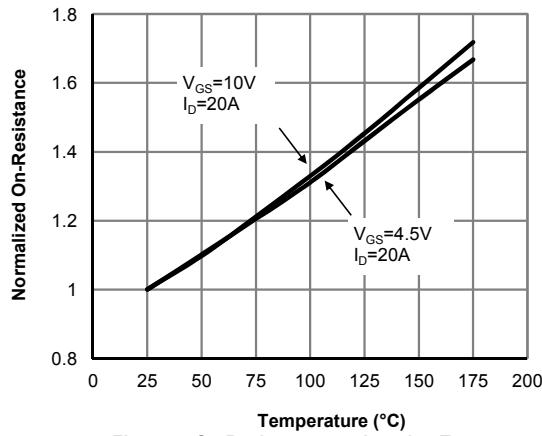
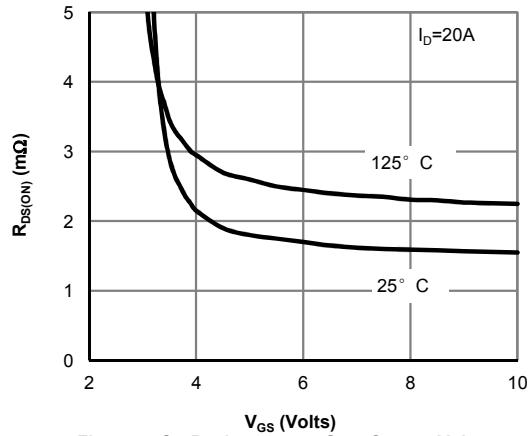
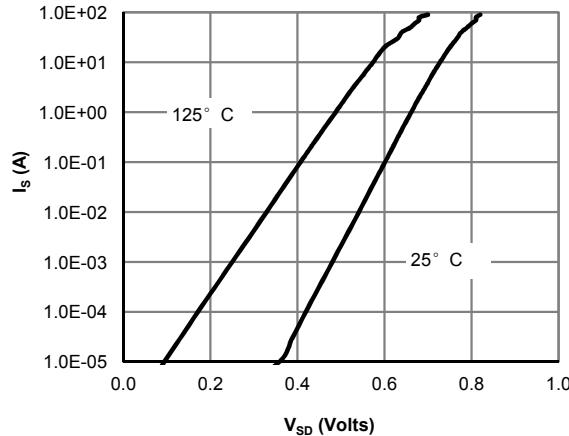
E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

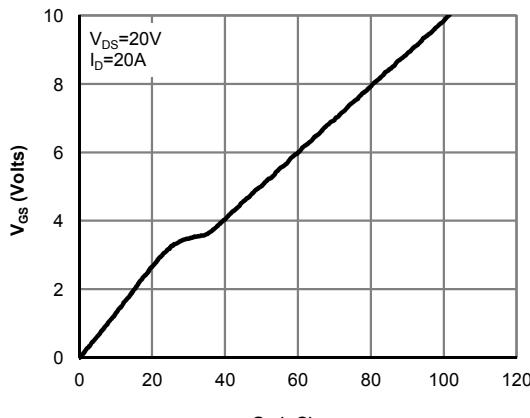
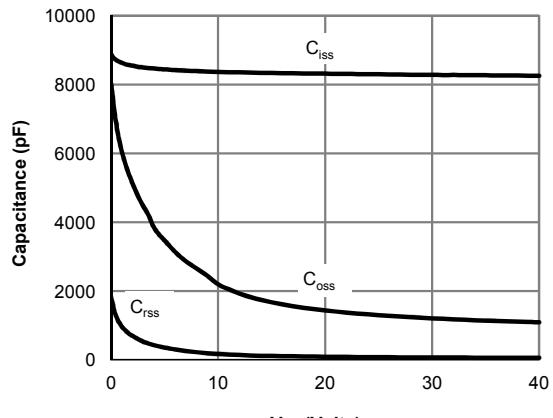
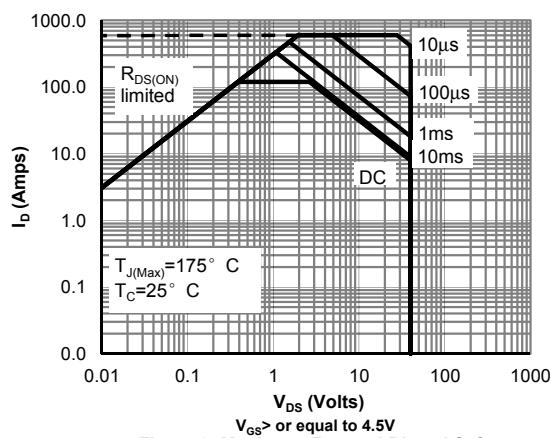
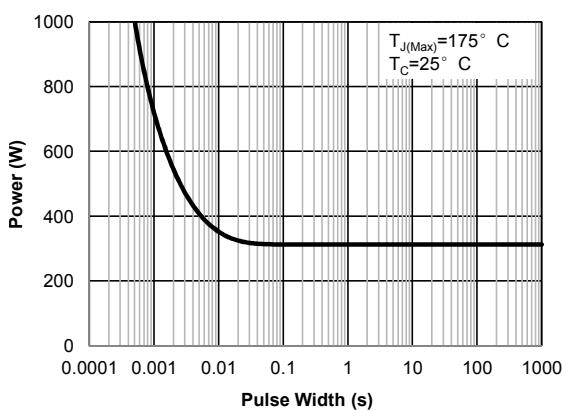
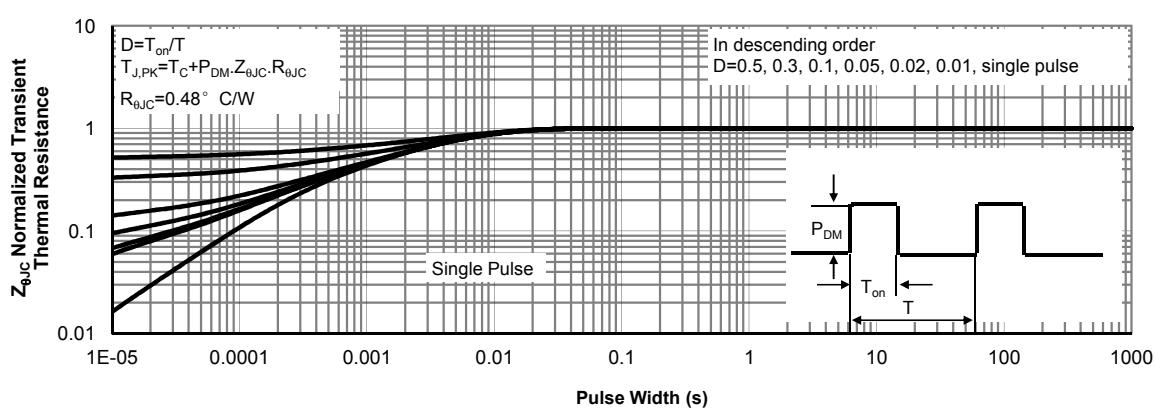
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{ C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{ C}$ .

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area for AOT2142L (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Case for AOT2142L (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance for AOT2142L (Note F)**

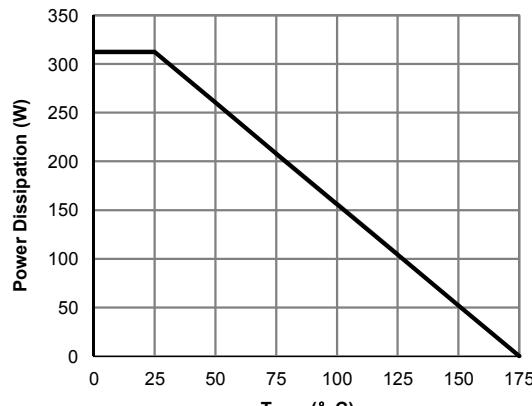
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 12: Power De-rating for AOT2142L  
 (Note F)

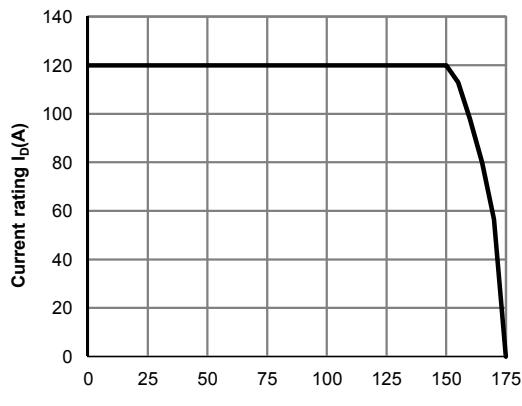


Figure 13: Current De-rating for AOT2142L  
 (Note F)

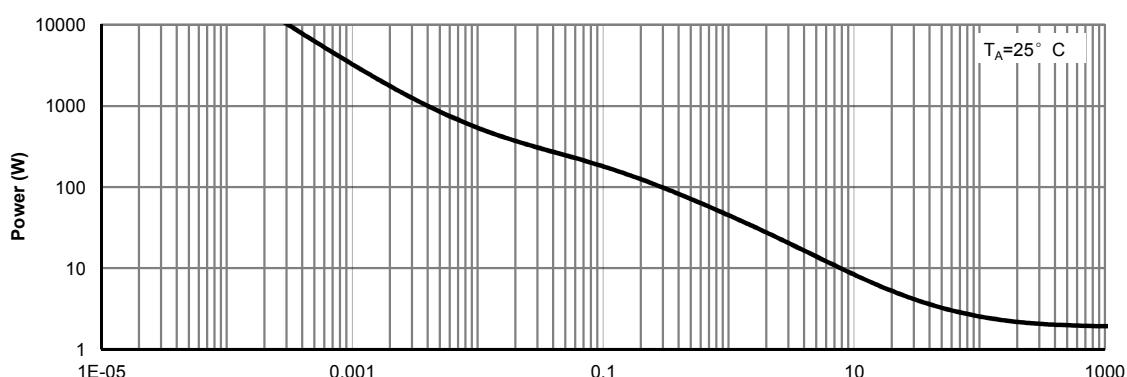


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

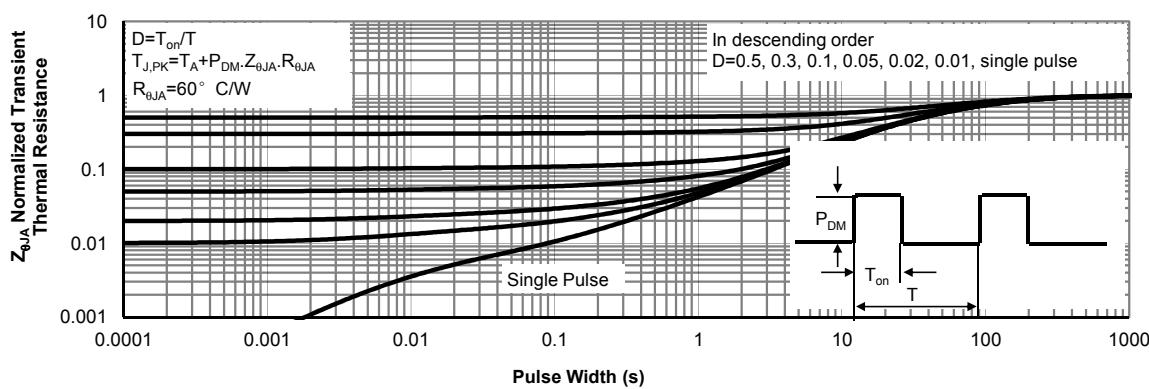


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

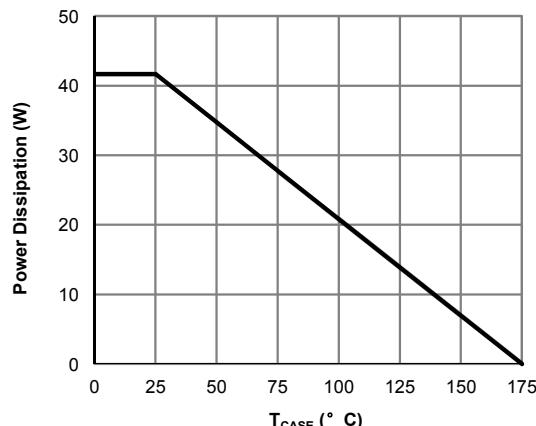
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 16: Power De-rating for AOTF2142L  
 (Note F)

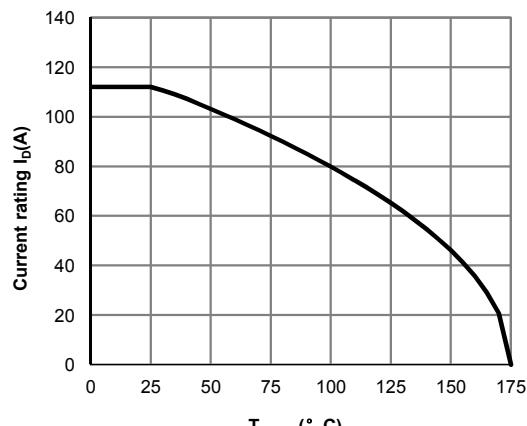


Figure 17: Current De-rating for AOTF2142L  
 (Note F)

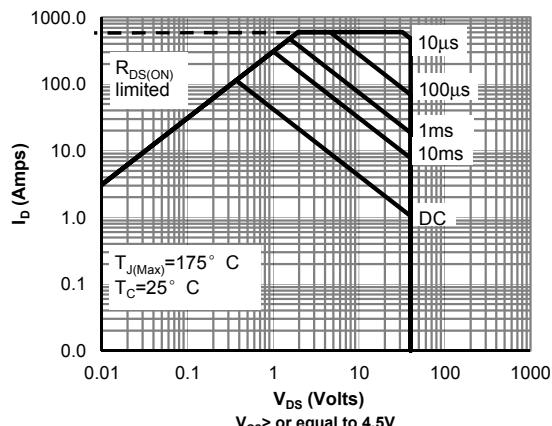


Figure 18: Maximum Forward Biased  
 Safe Operating Area for AOTF2142L  
 (Note F)

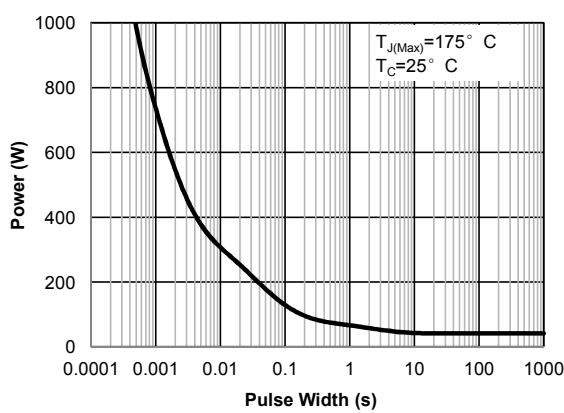


Figure 19: Single Pulse Power Rating Junction-to-  
 Case for AOTF2142L (Note F)

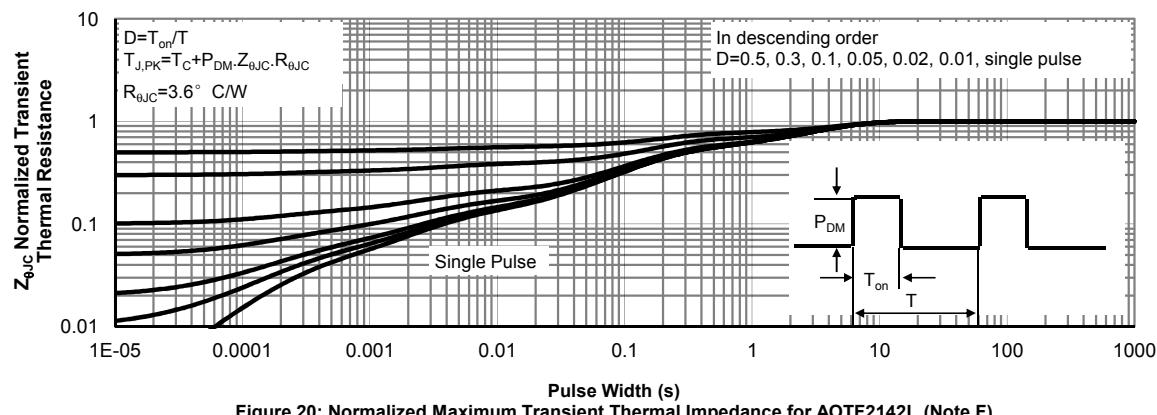
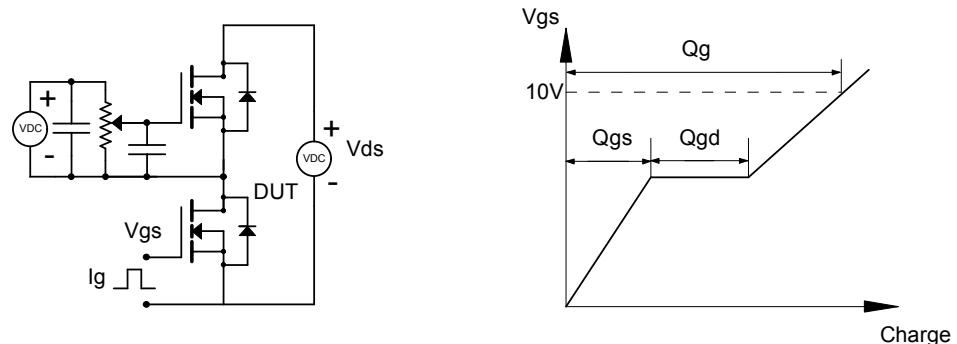
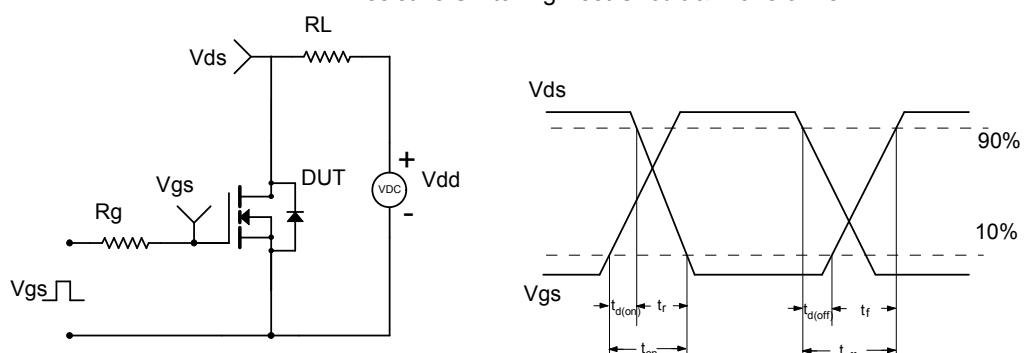
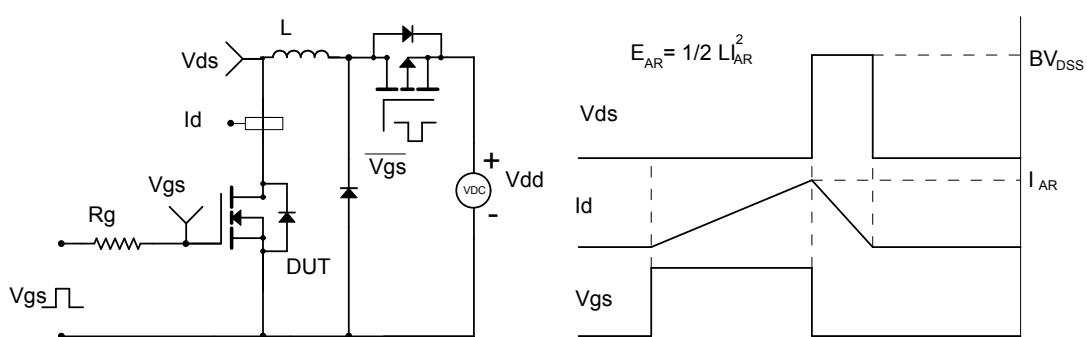


Figure 20: Normalized Maximum Transient Thermal Impedance for AOTF2142L (Note F)

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
